SCANFLEX® II CUBE
Multifunctional JTAG/Boundary Scan Controller

- high-performance controller for embedded test and programming
- outstanding flexibility through multifunctional I/O channels and FPGA instrumentation for mixed-signal and high-speed test
- high modularity and scalability through configurable TAP interface cards and additional I/O modules
- integrated compact unit controllable via USB 3.0 and GBit LAN
Technical specification

**SCANFLEX® II CUBE** - Boundary Scan Controller

<table>
<thead>
<tr>
<th>Parameters</th>
<th>Value</th>
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<tbody>
<tr>
<td>number of TAP slots</td>
<td>8 (independent and individually configurable with TAP plug-in card)</td>
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<tr>
<td>maximum TCK frequency</td>
<td>20/50/100 MHz (adjustable via software)</td>
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<tr>
<td>parallel I/O channels</td>
<td>64 mixed-signal channels combined with FPGA, individually configurable as input, output, tri-state, via software programmable V&lt;sub&gt;DD&lt;/sub&gt; 0.9-3.6 V (8 groups with 8 I/O)</td>
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<td>maximum number of I/O modules</td>
<td>30 modules via external SFX carrier + 1 module on top of the controller</td>
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<td>integrated technologies</td>
<td>SPACE™, HYSCAN™, ADYCS™, ChipVORX®, FastScale™</td>
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### Embedded test
- support of latest technologies such as Processor Emulation Test, FPGA Assisted Test and Embedded Diagnostics Test
- synchronization with multifunctional I/O channels and ChipVORX® FPGA instruments

### Expandability
- support of up to 31 parallel controlled SCANFLEX® I/O modules
- scalable number of one to eight TAPs
- interfaces for additional debug and control components

### Adaptability
- transmission over long distances of up to four meter to the target without TCK reduction or transmission problems
- software-parameterized I/O (slew rate, impedance, termination)
- via software selectable protocols (JTAG, DAP, COP, SWD, UART, BDM, SBW)

### Embedded programming
- high-speed programming of Flash components like NAND, NOR, SPI, I'C, eMMC etc. (also via I/O)
- universal programming of microcontrollers
- FPGA/PLD programming

### High performance
- use of powerful multi-core processors and FPGAs
- simultaneous operation at up to 100 MHz on all TAPs
- operation at up to 100 MHz on I/O channels
- support for gang operations

### Software
- integrated into Embedded JTAG Solutions platform SYSTEM CASCON™
- Plug and Play integration in 3rd party systems
- open mix of test and programming procedures in one software environment

### Technical specification

**SCANFLEX® II CUBE**
Flexible controller for embedded test and programming

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Made in Germany

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